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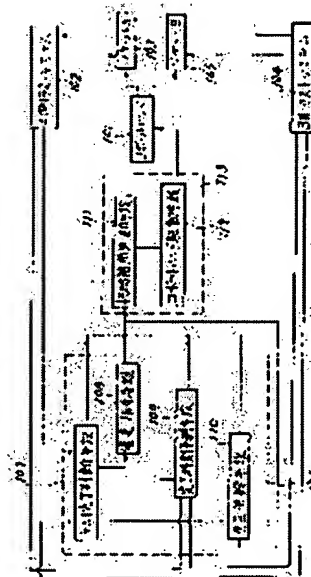
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(54) IC TESTING DEVICE

(57)Abstract:

PURPOSE: To shorten a test time by predicting a system which completes a test first between two test systems and holding a robot hand for inspected body supply ready on the system side.

CONSTITUTION: This device is provided with an A-side test system 102 which tests a 1st body to be inspected and a B-side test system 104 which tests a 2nd body to be inspected. A priority indicating means 108 indicates no priority, a completion period predicting means 109 computes the test completion period of both. Then an indication is sent to a microcomputer 113 which a robot hand driving means 112 and a supply position judging means 111 to hold the robot hand 101 ready in the test system which finished a test first. Thus, the waiting time in the test is utilized to perform other processes of transporting the body to be inspected and the test time can be shortened.



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